imall

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832 Email & Skype: info@chipsmall.com Web: www.chipsmall.com Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China





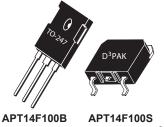


APT14F100B APT14F100S

1000V, 14A, 0.98Ω Max, t_{rr} ≤240ns

N-Channel FREDFET

Power MOS 8TM is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced t_{rr} , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of C_{rss}/C_{iss} result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



Single die FREDFET



FEATURES

- Fast switching with low EMI
- Low t_{rr} for high reliability
- Ultra low C_{rss} for improved noise immunity
- Low gate charge
- Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- ZVS phase shifted and other full bridge
- Half bridge
- PFC and other boost converter
- Buck converter
- Single and two switch forward
- Flyback

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
1_	Continuous Drain Current @ T _C = 25°C	14	
'D	Continuous Drain Current @ T _C = 100°C	9	А
I _{DM}	Pulsed Drain Current ^①	56	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy ©	875	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	7	А

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Мах	Unit	
P _D	Total Power Dissipation @ $T_{C} = 25^{\circ}C$			500	W	
R _{θJC}	Junction to Case Thermal Resistance			0.25 °C/W		
R _{ecs}	Case to Sink Thermal Resistance, Flat, Greased Surface		0.11		C/W	
T _J ,T _{STG}	Operating and Storage Junction Temperature Range	-55		150	- °C	
TL	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W _T	Package Weight		0.22		oz	
			5.9		g	
Torque	Mounting Torque (TO-247 Package), 6-32 or M3 screw			10	in∙lbf	
	Mounting Torque (TO-247 Fackage), 0-52 of M5 Sciew			1.1	N∙m	

Microsemi Website - http://www.microsemi.com

Static Characteristics

T_J = 25°C unless otherwise specified

APT14F100B S

Symbol	Parameter	Test Conditions	Min	Тур	Мах	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	V _{GS} = 0V, I _D = 250µA	1000			V
$\Delta V_{BR(DSS)} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, $I_D = 250 \mu A$		1.15		V/°C
R _{DS(on)}	Drain-Source On Resistance ^③	V _{GS} = 10V, I _D = 7A		0.82	0.98	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 1mA$	2.5	4	5	V
$\Delta V_{GS(th)} / \Delta T_J$	Threshold Voltage Temperature Coefficient			-10		mV/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 1000V$ $T_{J} = 25^{\circ}C$			250	μA
DSS	Zelo Gale voltage Drain Current	$V_{GS} = 0V$ $T_{J} = 125^{\circ}C$			1000	
I _{GSS}	Gate-Source Leakage Current	$V_{GS} = \pm 30V$			±100	nA

Dynamic Characteristics

T_J = 25°C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
9 _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 7A		16		S
C _{iss}	Input Capacitance			3965		
C _{rss}	Reverse Transfer Capacitance	V _{GS} = 0V, V _{DS} = 25V f = 1MHz		55		
C _{oss}	Output Capacitance	1 111112		335		pF
C _{o(cr)} ⊕	Effective Output Capacitance, Charge Related	$V_{GS} = 0V, V_{DS} = 0V \text{ to } 667V$		135		
C _{o(er)} (5	Effective Output Capacitance, Energy Related			70		
Q _g	Total Gate Charge			120		
Q _{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 7A,$		21		nC
Q _{gd}	Gate-Drain Charge	$V_{\rm DS} = 500V$		60		
t _{d(on)}	Turn-On Delay Time	Resistive Switching		28		
t _r	Current Rise Time	V _{DD} = 667V, I _D = 7A		29		ns
t _{d(off)}	Turn-Off Delay Time	R _G = 4.7Ω [®] , V _{GG} = 15V		95		115
t _f	Current Fall Time			26		

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Тур	Мах	Unit
۱ _s	Continuous Source Current (Body Diode)	MOSFET symbol showing the			14	А
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n junction diode (body diode)			56	~
V _{SD}	Diode Forward Voltage	$I_{SD} = 7A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.0	V
t _{rr}		$T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$		205	240	ns
'n	Reverse Recovery Time			355	430	115
Q _{rr}	Reverse Recovery Charge	$I_{SD} = 7A^{\textcircled{3}}$ $T_J = 25^{\circ}C$		0.90		
~m		$di_{SD}/dt = 100A/\mu s$ $T_J = 125^{\circ}C$		2.20		- μC
I _{rrm}	Reverse Recovery Current	$V_{DD} = 100V$ $T_{J} = 25^{\circ}C$		8.90		А
		T _J = 125°C		12.90		A
dv/dt	Peak Recovery dv/dt	I _{SD} ≤ 7A, di/dt ≤1000A/µs, V _{DD} = 400V, T _J = 125°C			25	V/ns

(1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

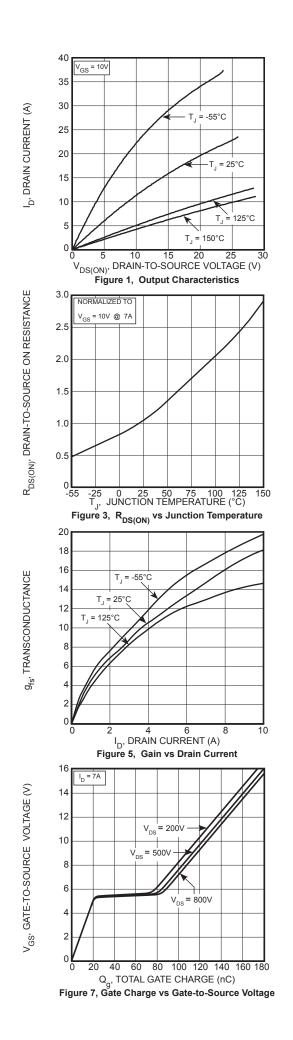
(2) Starting at $T_J = 25^{\circ}C$, L = 35.71mH, $R_G = 25\Omega$, $I_{AS} = 7A$.

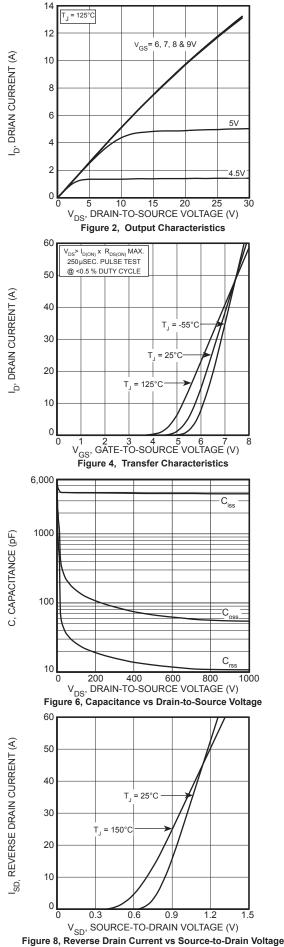
(3) Pulse test: Pulse Width < 380μ s, duty cycle < 2%.

(4) C_{o(cr)} is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}.
(5) C_{o(er)} is defined as a fixed capacitance with the same stored energy as C_{OSS} with V_{DS} = 67% of V_{(BR)DSS}. To calculate C_{o(er)} for any value of V_{DS} less than V_{(BR)DSS}, use this equation: C_{o(er)} = -1.15E-7/V_{DS}² + 2.03E-8/V_{DS} + 3.93E-11.

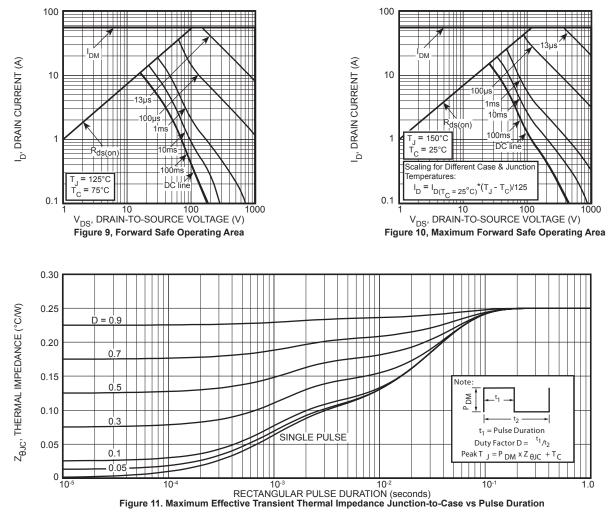
6 R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



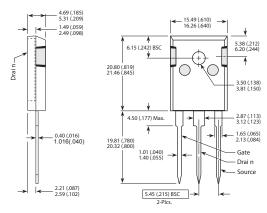


050-8160 Rev D 8-2011

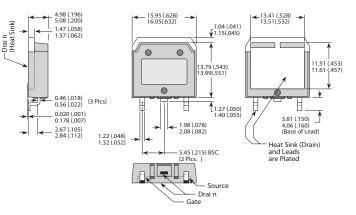


TO-247 (B) Package Outline

(e1) SAC: Tin, Silver, Copper



D³PAK Package Outline © 100% Sn Plated



Dimensions in Millimeters (Inches)

Dimensions in Millimeters (Inches)